

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET
M122-1427SERIAL NO.
Filed HerewithLIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
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GROUP

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JK	AA	4,954,867	09/04/90	Hosaka	257	639	
JK	AB	5,441,797	08/15/95	Hogan et al.	428	209	
JK	AC	5,472,827	12/05/95	Ogawa et al.	430	315	
JK	AD	5,674,356	10/07/97	Nagayama	438	694	
JK	AE	5,710,067	01/20/98	Foot et al.	438	636	
JK	AF	5,731,242	03/24/98	Parat et al.	438	586	
JK	AG	5,741,721	04/21/98	Stevens	438	396	
JK	AH	5,759,755	06/02/98	Park et al.	430	512	
JK	AI	5,838,052	11/17/98	McTeer	257	437	
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
JK	AL	JP06067019A	1/92	Japan (Abstract)	-	-		
JK	AM	0 471 185 A2	2/92	EPO	-	-		
JK	AN	0 588 087 A2	3/94	EPO	-	-		
JK	AO	0 588 087 A3	3/94	EPO	-	-		
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

JK	AR	ARTICLE: Bencher, C. et al., "Dielectric antireflective coatings for DUV lithography", Solid State Technology (March 1997), pp. 109-114.
JK	AS	ARTICLE: Dammel, R. R. et al., "Dependence of Optical Constants of AZ® BARLi™ Bottom Coating on Back Conditions", SPIE Vol. 3049 (1997), pp. 963-973.
JK	AT	TEXT: Heavens, O. S., "Optical Properties of Thin Solid Films", pp. 48-49.

EXAMINER

JK E. E. E.

DATE CONSIDERED

2/28/01

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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APPLICANT
Micron Technology, Inc.

09/559903

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U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
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	AF					
	AG					
	AH					
	AI					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

9/22	AR	TEXT: Jenkins, F. et al., "Fundamentals of Optics", Properties of Light, pp. 9-10.
9/22	AS	TEXT: Wolf, S. et al., "Silicon Processing for the VLSI Era", Vol. 1, pp. 437-441.
	AT	

EXAMINER

J. E. Eubank

DATE CONSIDERED

9/28/01

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1427	SERIAL NO. 09/559,903
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.	
				FILING DATE April 26, 2000	GROUP 2825

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
9/20/01	AA	App. 09/030,618 as filed and amended	2/25/98	Holscher		02/98	
	AB						
	AC						
	AD						
	AE						
	AF						
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	AI						
	AJ						
	AK						
	AL						

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AR		
	AS		
	AT		

EXAMINER 9/20/01	DATE CONSIDERED 9/20/01
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					FILING DATE April 26, 2000		GROUP 2825	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
ym	AA	5,968,324	10/99	Cheung et al.	204	192.28		
ym	AB	5,872,385	02/99	Taft et al.	257	437		
ym	AC	5,883,011	04/99	Lin et al.	438	747		
ym	AD	5,960,289	09/99	Tsui et al.	438	275		
ym	AE	6,020,243	02/00	Wallace et al.	438	287		
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
ym	AM	US 99/20029	08/99	PCT Search Report				
ym	AN	US 99/20030	08/99	PCT Search Report				
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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	AS							
	AT							
EXAMINER J. C. Eckert				DATE CONSIDERED 9/28/01				
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
gk	AA	5,472,829	Ogawa	430	325		
gk	AB	5,591,566	Ogawa	430	325		
gk	AC	5,641,607	Ogawa et al.	430	222.1		
gk	AD	5,648,202	Ogawa et al.	430	325		
gk	AE	5,677,111	Ogawa	430	313		
gk	AF	5,670,297	Ogawa et al.	430	318		
gk	AG	5,698,352	Ogawa et al.	430	14		
gk	AH	5,831,321	Nagayama	257	412		
gk	AI	5,034,348	Hartswick et al.	438	453		
gk	AJ	6,008,124	Sekiguchi et al.	438	653		
gk	AK	5,340,621	Matsumoto et al.	427	571		
gk	AL	5,600,165	Tsukamoto et al.	257	323		
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
gk	AM	0-778496 A2/A3	06/97	EPO			
gk	AN	9-55351	02/97	Japan			
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
gk	AR	McKenzie, D. et al., "New Technology for PACVD", Surface and Coatings Technology 82 (1996), pp. 326-333.					
gk	AS	Shibata, Noburu, "Plasma-Chemical Vapor-Deposited Silicon Oxide/Silicon Oxynitride Double-Layer Antireflective Coating for Solar Cells", Jap. Journ. of Applied Physics, Vol. 30, No. 5, May 1991, pp. 997-1001.					
	AT						
EXAMINER				DATE CONSIDERED			
gk				9/20/91			
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